

Search Notes

Application/Control No.

09/704,755

Examiner

Daniel Pan

Applicant(s)/Patent under
Reexamination

FURUKAWA, HIDEAKI

Art Unit

2183

SEARCHED

| Class | Subclass | Date | Examiner |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
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| west pgp uspat jpoabs epoabs derwent IEEE IBM TD NPL 399/18-22 358/401 709/211,232 712/227, 248 | 11/17/2007 | dp |
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